

IGBT³ Chip

Features:

- 600V Trench & Field Stop technology
- low V_{CE(sat)}
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

This chip is used for:

- power module
- Applications:
- drives



Chip Type	V _{CE}	<i>I</i> c	Die Size	Package
SIGC100T60R3	600V	200A	9.73 x 10.23 mm ²	sawn on foil

Mechanical Parameter

Raster size	9.73 x 10.23		
Emitter pad size (incl. gate pad)	(4.256 x 1.938) x 4 (4.256 x 2.356) x 4	mm ²	
Gate pad size	1.615 x 0.817		
Area total	99.5		
Thickness	70	μm	
Wafer size	150	mm	
Max.possible chips per wafer	126		
Passivation frontside	Photoimide		
Pad metal	3200 nm AlSiCu		
Backside metal	Ni Ag –system suitable for epoxy and soft solder die bonding		
Die bond	Electrically conductive glue or solder		
Wire bond	Al, <500µm		
Reject ink dot size	Ø 0.65mm ; max 1.2mm		
Recommended storage environment	Store in original container, in dry nitrogen, in dark environment, < 6 month at an ambient temperature of 23°C		



Maximum Ratings

Parameter	Symbol	Value	Unit	
Collector-Emitter voltage, <i>T</i> _{vj} =25 °C	V _{CE}	600	V	
DC collector current, limited by $T_{vj max}$	I _C	1)	А	
Pulsed collector current, t_p limited by $T_{vj max}$	I _{c,puls}	600	А	
Gate emitter voltage	V _{GE}	±20	V	
Junction temperature range	T _{vj}	-40 +175	°C	
Operating junction temperature	T _{vj}	-40+150	°C	
Short circuit data ²) V_{GE} = 15V, V_{CC} = 360V, T_{vj} = 150°C	t _{sc}	6	μs	
Reverse bias safe operating area ²⁾ (RBSOA)	$I_{C,max}$ = 400A, $V_{CE,max}$ = 600V $T_{vj} \le 150^{\circ}C$			

¹⁾ depending on thermal properties of assembly

²) not subject to production test - verified by design/characterization

Value Symbol Conditions Unit Parameter min. typ. max. Collector-Emitter breakdown voltage $V_{GE}=0V$, $I_C=4$ mA 600 V_{(BR)CES} V_{GE} =15V, I_{C} =200A 1.05 1.45 1.85 V Collector-Emitter saturation voltage V_{CEsat} Gate-Emitter threshold voltage $I_{\rm C}$ =3.2mA , $V_{\rm GE}$ = $V_{\rm CE}$ 5.0 5.8 $V_{GE(th)}$ 6.5 Zero gate voltage collector current V_{CE} =600V , V_{GE} =0V 10.1 μΑ I_{CES} *V*_{CE}=0V , *V*_{GE}=20V Gate-Emitter leakage current 600 nA I_{GES} 2 Integrated gate resistor r_G Ω

Static Characteristic (tested on wafer), T_{vi} =25 °C

Dynamic Characteristic (not subject to production test - verified by design / characterization), T_{vi} =25 °C

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Parameter	Symbol	Conditions	min.	typ.	max.	Unit
Input capacitance	Cies	V _{CE} =25V,		12335		
Output capacitance	C _{oes}	$V_{GE}=0V$,		769		pF
Reverse transfer capacitance	Cres	<i>f</i> =1MHz		366		

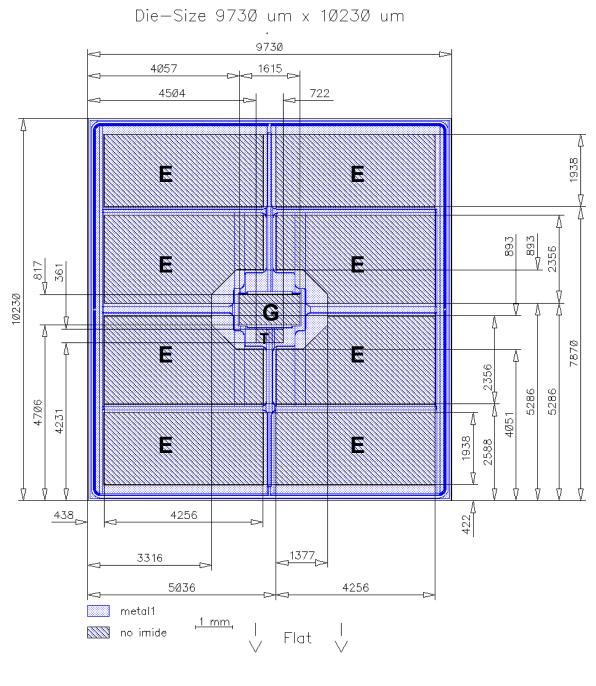


Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



Chip Drawing



E = Emitter pad

G = Gate pad

T = Test pad do not contact



Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date
2.1	Change max.possible chips per wafer	04.05.2010

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